

Product Change Notice (PCN)

Subject: Wafer Fabrication Site Change for the controller die in the ISL99140IRZ* Intersil Product

Publication Date: 4/19/2016

Effective Date: 7/19/2016

Revision Description:

Initial Release

Description of Change:

This notice is to inform you, as a result of declining volumes, Intersil has re-installed its proprietary P6 technology in the Intersil Palm Bay, Florida facility for wafer fabrication. This technology initially ran in Palm Bay from 2002 to 2004. Intersil has invested ~ \$30M to upgrade the facility to add 200mm capability to match the current tools used, as well as in-line unit process and electrical parameters.

Impacted Products: ISL99140IRZ-T; ISL99140IRZ-TS2568

Reason for Change:

The move back to Palm Bay will position Intersil to guarantee continuity of supply to our customers as the volumes on the technology continue to decline. The site-specific process technology qualification has completed.

Impact on fit, form, function, quality & reliability:

The change will have no impact on the form, fit, function, quality, reliability and environmental compliance of the devices.

Product Identification:

There will be no change to the product data sheet specifications or external marking of the packaged products. Product affected by this change is identifiable via internal traceability systems.

Qualification status: Complete, see attached

Sample availability: Specific product samples available with 4 month ARO

Device material declaration: Available upon request

Questions or requests pertaining to this change notice, including additional data or samples, must be sent to Intersil within 30 days of the publication date.

For additional information regarding this notice, please contact your regional change coordinator (below)			
Americas: PCN-US@INTERSIL.COM	Europe: PCN-EU@INTERSIL.COM	Japan: PCN-JP@INTERSIL.COM	Asia Pac: PCN-APAC@INTERSIL.COM

Appendix A - Qualification Results

Stress / Conditions	Duration	ISL6312CRZ 48 Lead 7x7 QFN	ISL6420AIRZ 20 Lead 4x4 QFN	ISL6536IBZ 8 Lead SOIC
Mositure Sensitivity Classification		N = 48 Pass L3 PBFREE	N = 22 Pass L2 PBFREE	N = 44 Pass L1 PBFREE
High Temperature Operating Life T _A @ 125°C	1000 hrs	N = 156 Pass	N = 155 Pass	N = 79 Pass
Biased HAST +130°C / 85% RH	96 hrs	N = 78 Pass	N = 78 Pass	N = 80 Pass
High Temperature Storage T _A - +150°C	1000 hrs	N = 222 ¹ Pass	N = 78 Pass	N = 78 Pass
Unbiased HAST + 130°C / 85% RH	96 hrs	N = 240 Pass	N = 78 Pass	N = 80 Pass
Temp Cycle +150°C / -65°C	500 cy	N = 240 Pass	N = 80 Pass	N = 80 Pass

Notes:

1. Single unit failure, corrective action completed